# **Quad 3-State Noninverting Buffers**

### **High-Performance Silicon-Gate CMOS**

The MC74HC125A and MC74HC126A are identical in pinout to the LS125 and LS126. The device inputs are compatible with standard CMOS outputs; with pullup resistors, they are compatible with LSTTL outputs.

The HC125A and HC126A noninverting buffers are designed to be used with 3-state memory address drivers, clock drivers, and other bus-oriented systems. The devices have four separate output enables that are active-low (HC125A) or active-high (HC126A).

#### **Features**

- Output Drive Capability: 15 LSTTL Loads
- Outputs Directly Interface to CMOS, NMOS, and TTL
- Operating Voltage Range: 2.0 to 6.0 V
- Low Input Current: 1.0 μA
- High Noise Immunity Characteristic of CMOS Devices
- In Compliance with the JEDEC Standard No. 7A Requirements
- Chip Complexity: 72 FETs or 18 Equivalent Gates
- Pb-Free Packages are Available



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MARKING DIAGRAMS

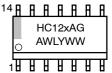


PDIP-14 [ N SUFFIX CASE 646 [





SOIC-14 D SUFFIX CASE 751A

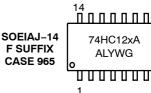




TSSOP-14 DT SUFFIX CASE 948G







A = Assembly Location

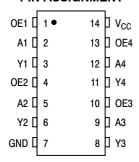
L, WL = Wafer Lot Y, YY = Year W, WW = Work Week G = Pb-Free Package ■ = Pb-Free Package

(Note: Microdot may be in either location)

#### **ORDERING INFORMATION**

See detailed ordering and shipping information in the package dimensions section on page 4 of this data sheet.

#### **PIN ASSIGNMENT**



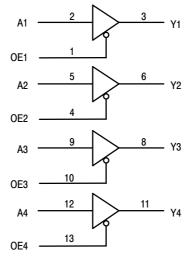
## FUNCTION TABLE

HC125A				
In	outs	Output		
Α	OE	Υ		
Н	L	Н		
L	L	L		
Х	Н	Z		

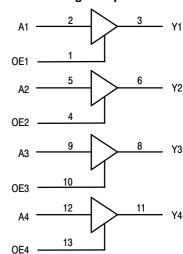
HC126A					
Inputs Output					
Α	OE	Υ			
Н	Н	Н			
L	Н	L			
Χ	L	Z			

#### **LOGIC DIAGRAM**

# HC125A Active-Low Output Enables



HC126A Active-High Output Enables



PIN 14 = V<sub>CC</sub> PIN 7 = GND

#### **MAXIMUM RATINGS**

Symbol	Parameter	Value	Unit
V <sub>CC</sub>	DC Supply Voltage (Referenced to GND)	- 0.5 to + 7.0	V
V <sub>in</sub>	DC Input Voltage (Referenced to GND)	$-$ 0.5 to V $_{\rm CC}$ + 0.5	V
V <sub>out</sub>	DC Output Voltage (Referenced to GND)	$-0.5$ to $V_{CC}$ + 0.5	V
l <sub>in</sub>	DC Input Current, per Pin	±[ <b>2</b> 0	mA
l <sub>out</sub>	DC Output Current, per Pin	± <b>3</b> 5	mA
I <sub>CC</sub>	DC Supply Current, V <sub>CC</sub> and GND Pins	±[ <b>7</b> 5	mA
P <sub>D</sub>	Power Dissipation in Still Air Plastic DIP† SOIC Package† TSSOP Package†	750 500 450	mW
T <sub>stg</sub>	Storage Temperature	- 65 to + 150	°C
TL	Lead Temperature, 1 mm from Case for 10 Seconds (Plastic DIP, SOIC or TSSOP Package)	260	°C

This device contains protection circuitry to guard against damage due to high static voltages or electric fields. However, precautions must be taken to avoid applications of any voltage higher than maximum rated voltages to this high-impedance circuit. For proper operation,  $V_{in}$  and  $V_{out}$  should be constrained to the range GND  $\leq$  ( $V_{in}$  or  $V_{out}$ )  $\leq$   $V_{CC}$ .

Unused inputs must always be tied to an appropriate logic voltage level (e.g., either GND or  $V_{\rm CC}$ ). Unused outputs must be left open.

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

†Derating — Plastic DIP: – 10 mW/°C from 65° to 125°C SOIC Package: – 7 mW/°C from 65° to 125°C

TSSOP Package:  $-6.1 \text{ mW/}^{\circ}\text{C}$  from 65° to 125°C For high frequency or heavy load considerations, see Chapter 2 of the ON Semiconductor High–Speed CMOS Data Book (DL129/D).

#### RECOMMENDED OPERATING CONDITIONS

Symbol	Parameter	Parameter		Max	Unit
V <sub>CC</sub>	DC Supply Voltage (Referenced to GND)		2.0	6.0	V
V <sub>in</sub> , V <sub>out</sub>	DC Input Voltage, Output Voltage (Referenced to GND)		0	V <sub>CC</sub>	V
T <sub>A</sub>	Operating Temperature, All Package Types		<b>– 55</b>	+ 125	°C
t <sub>r</sub> , t <sub>f</sub>	(Figure 1) V <sub>C</sub>	C = 2.0 V C = 4.5 V C = 6.0 V	0 0 0	1000 500 400	ns

#### DC ELECTRICAL CHARACTERISTICS (Voltages Referenced to GND)

				Gu	aranteed Li	mit	
Symbol	Parameter	Test Conditions	V <sub>CC</sub>	– 55 to 25°C	≤ <b>85</b> °C	≤ 125°C	Unit
V <sub>IH</sub>	Minimum High-Level Input Voltage	$V_{out} = V_{CC} - 0.1 \text{ V}$	2.0	1.5	1.5	1.5	V
		$ I_{\text{out}}  \le 20 \mu\text{A}$	3.0	2.1	2.1	2.1	
			4.5	3.15	3.15	3.15	
			6.0	4.2	4.2	4.2	
V <sub>IL</sub>	Maximum Low-Level Input Voltage	V <sub>out</sub> = 0.1 V	2.0	0.5	0.5	0.5	V
		$ I_{out}  \le 20 \mu\text{A}$	3.0	0.9	0.9	0.9	
			4.5	1.35	1.35	1.35	
			6.0	1.8	1.8	1.8	
V <sub>OH</sub>	Minimum High-Level Output	$V_{in} = V_{IH}$	2.0	1.9	1.9	1.9	V
	Voltage	$ I_{out}  \leq 20 \mu\text{A}$	4.5	4.4	4.4	4.4	
			6.0	5.9	5.9	5.9	
		$V_{in} = V_{IH}$ $ I_{out}  \le 3.6 \text{ mA}$	3.0	2.48	2.34	2.2	
		$ I_{out}  \le 6.0 \text{ mA}$	4.5	3.98	3.84	3.7	
		$ I_{out}  \le 7.8 \text{ mA}$	6.0	5.48	5.34	5.2	
V <sub>OL</sub>	Maximum Low-Level Output	$V_{in} = V_{IL}$	2.0	0.1	0.1	0.1	V
	Voltage	$ I_{out}  \leq 20 \mu\text{A}$	4.5	0.1	0.1	0.1	
			6.0	0.1	0.1	0.1	
		$V_{in} = V_{IL}$ $ I_{out}  \le 3.6 \text{ mA}$	3.0	0.26	0.33	0.4	
		$ I_{out}  \le 6.0 \text{ mA}$	4.5	0.26	0.33	0.4	
		$ I_{out}  \le 7.8 \text{ mA}$	6.0	0.26	0.33	0.4	
l <sub>in</sub>	Maximum Input Leakage Current	V <sub>in</sub> = V <sub>CC</sub> or GND	6.0	±[0.1	±[1.0	±∏1.0	μΑ
loz	Maximum Three-State Leakage	Output in High-Impedance State	6.0	±[0.5	±[5.0	±[10	μΑ
	Current	V <sub>in</sub> = V <sub>IL</sub> or V <sub>IH</sub>					
		V <sub>out</sub> = V <sub>CC</sub> or GND					
Icc	Maximum Quiescent Supply Current	V <sub>in</sub> = V <sub>CC</sub> or GND	6.0	4.0	40	160	μΑ
	(per Package)	I <sub>out</sub> = 0 μA					

NOTE: Information on typical parametric values can be found in Chapter 2 of the ON Semiconductor High-Speed CMOS Data Book (DL129/D).

#### AC ELECTRICAL CHARACTERISTICS ( $C_L = 50 \text{ pF}$ , Input $t_r = t_f = 6.0 \text{ ns}$ )

			Gu	aranteed Li	mit	
Symbol	Parameter	V <sub>CC</sub>	– 55 to 25°C	≤ <b>85</b> °C	≤ 125°C	Unit
t <sub>PLH</sub> ,	Maximum Propagation Delay, Input A to Output Y	2.0	90	115	135	ns
t <sub>PHL</sub>	(Figures 1 and 3)	3.0	36	45	60	
		4.5	18	23	27	
		6.0	15	20	23	
t <sub>PLZ</sub> ,	Maximum Propagation Delay, Output Enable to Y	2.0	120	150	180	ns
t <sub>PHZ</sub>	(Figures 2 and 4)	3.0	45	60	80	
		4.5	24	30	36	
		6.0	20	26	31	
t <sub>PZL</sub> ,	Maximum Propagation Delay, Output Enable to Y	2.0	90	115	135	ns
t <sub>PZH</sub>	(Figures 2 and 4)	3.0	36	45	60	
		4.5	18	23	27	
		6.0	15	20	23	
t <sub>TLH</sub> ,	Maximum Output Transition Time, Any Output	2.0	60	75	90	ns
t <sub>THL</sub>	(Figures 1 and 3)	3.0	22	28	34	
		4.5	12	15	18	
		6.0	10	13	15	1
C <sub>in</sub>	Maximum Input Capacitance	-	10	10	10	pF
C <sub>out</sub>	Maximum 3-State Output Capacitance (Output in High-Impedance State)	-	15	15	15	pF

NOTE: For propagation delays with loads other than 50 pF, and information on typical parametric values, see Chapter 2 of the ON Semiconductor High-Speed CMOS Data Book (DL129/D).

		Typical @ 25°C, V <sub>CC</sub> = 5.0 V	
$C_{PD}$	Power Dissipation Capacitance (Per Buffer)*	30	pF

<sup>\*</sup>Used to determine the no-load dynamic power consumption: P<sub>D</sub> = C<sub>PD</sub> V<sub>CC</sub><sup>2</sup>f + I<sub>CC</sub> V<sub>CC</sub>. For load considerations, see Chapter 2 of the ON Semiconductor High-Speed CMOS Data Book (DL129/D).

#### **ORDERING INFORMATION**

Device	Package	Shipping <sup>†</sup>	
MC74HC125AN	PDIP-14		
MC74HC125ANG	PDIP-14 (Pb-Free)	25 Units / Rail	
MC74HC125AD	SOIC-14		
MC74HC125ADG	SOIC-14 (Pb-Free)	55 Units / Rail	
MC74HC125ADR2	SOIC-14		
MC74HC125ADR2G	SOIC-14 (Pb-Free)	2500 / Tape & Reel	
MC74HC125ADT	TSSOP-14*	0011 11 / 12 11	
MC74HC125ADTG	TSSOP-14*	96 Units / Rail	
MC74HC125ADTR2	TSSOP-14*	0500 / Tarra 0 Paral	
MC74HC125ADTR2G	TSSOP-14*	2500 / Tape & Reel	
MC74HC125AF	SOEIAJ-14		
MC74HC125AFG	SOEIAJ-14 (Pb-Free)	50 Units / Rail	
MC74HC125AFEL	SOEIAJ-14		
MC74HC125AFELG	SOEIAJ-14 (Pb-Free)	2000 / Tape & Reel	
MC74HC126AN	PDIP-14		
MC74HC126ANG	PDIP-14 (Pb-Free)	25 Units / Rail	
MC74HC126AD	SOIC-14		
MC74HC126ADG	SOIC-14 (Pb-Free)	55 Units / Rail	
MC74HC126ADR2	SOIC-14		
MC74HC126ADR2G	SOIC-14 (Pb-Free)	2500 / Tape & Reel	
MC74HC126ADTR2	TSSOP-14*	· •	
MC74HC126ADTR2G	TSSOP-14*		
MC74HC126AFEL	SOEIAJ-14		
MC74HC126AFELG	SOEIAJ-14 (Pb-Free)	2000 / Tape & Reel	

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.
\*This package is inherently Pb-Free.

#### **SWITCHING WAVEFORMS**

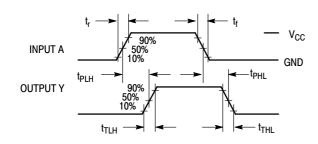


Figure 1.

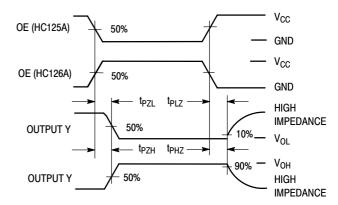
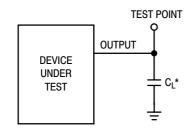
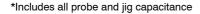


Figure 2.



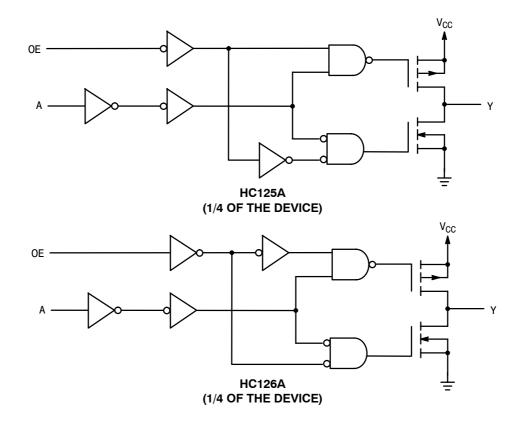


DEVICE UNDER TEST TEST POINT  $CONNECT TO V_{CC} WHEN TESTING t_{PLZ} AND t_{PZL} CONNECT TO GND WHEN TESTING t_{PHZ} and t_{PZH}.$ 

\*Includes all probe and jig capacitance

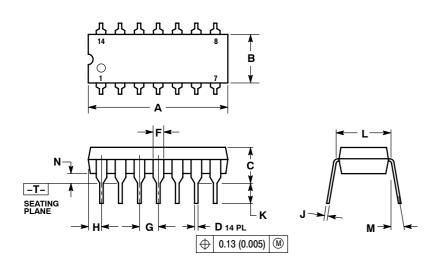
Figure 3. Test Circuit

Figure 4. Test Circuit



#### **PACKAGE DIMENSIONS**

PDIP-14 CASE 646-06 ISSUE P

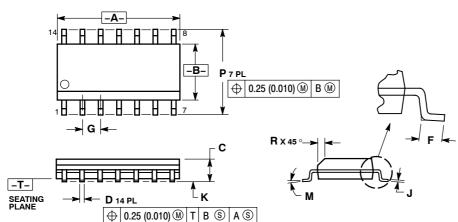


- NOTES:
  1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
  2. CONTROLLING DIMENSION: INCH.
  3. DIMENSION L TO CENTER OF LEADS WHEN FORMED PARALLEL.
  4. DIMENSION B DOES NOT INCLUDE MOLD FLASH.
  5. ROUNDED CORNERS OPTIONAL.

	INCHES		MILLIM	IETERS
DIM	MIN	MAX	MIN	MAX
Α	0.715	0.770	18.16	19.56
В	0.240	0.260	6.10	6.60
С	0.145	0.185	3.69	4.69
D	0.015	0.021	0.38	0.53
F	0.040	0.070	1.02	1.78
G	0.100	BSC	2.54 BSC	
Н	0.052	0.095	1.32	2.41
J	0.008	0.015	0.20	0.38
K	0.115	0.135	2.92	3.43
L	0.290	0.310	7.37	7.87
М		10 °		10 °
N	0.015	0.039	0.38	1.01

#### PACKAGE DIMENSIONS

SOIC-14 CASE 751A-03 **ISSUE H** 



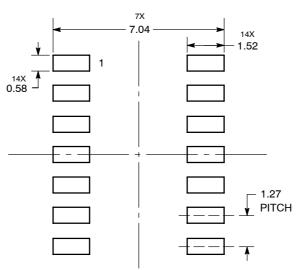
#### NOTES:

- 1. DIMENSIONING AND TOLERANCING PER

- 1. DIMENSIONING AND TOLEHANGING PER ANSI Y14.5M, 1982.
  2. CONTROLLING DIMENSION: MILLIMETER.
  3. DIMENSIONS A AND B DO NOT INCLUDE MOLD PROTRUSION.
  4. MAXIMUM MOLD PROTRUSION 0.15 (0.006) PER SIDE.
- PER SIDE.
  5. DIMENSION D DOES NOT INCLUDE
  DAMBAR PROTRUSION. ALLOWABLE
  DAMBAR PROTRUSION SHALL BE 0.127
  (0.005) TOTAL IN EXCESS OF THE D
  DIMENSION AT MAXIMUM MATERIAL
  CONDITION.

	MILLIMETERS		INC	HES
DIM	MIN	MAX	MIN	MAX
Α	8.55	8.75	0.337	0.344
В	3.80	4.00	0.150	0.157
С	1.35	1.75	0.054	0.068
D	0.35	0.49	0.014	0.019
F	0.40	1.25	0.016	0.049
G	1.27	BSC	0.050	BSC
J	0.19	0.25	0.008	0.009
K	0.10	0.25	0.004	0.009
М	0 °	7°	0 °	7 °
Р	5.80	6.20	0.228	0.244
R	0.25	0.50	0.010	0.019

#### **SOLDERING FOOTPRINT\***

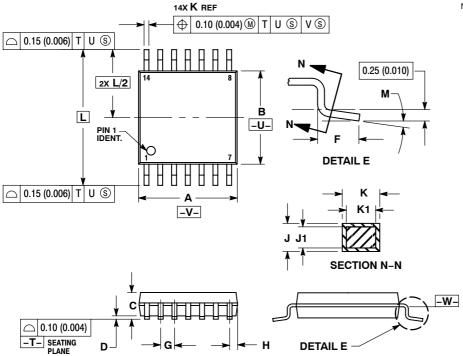


DIMENSIONS: MILLIMETERS

<sup>\*</sup>For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

#### PACKAGE DIMENSIONS

TSSOP-14 CASE 948G-01 **ISSUE B** 



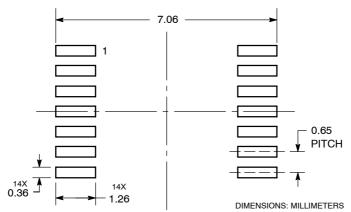
- NOTES:
  1. DIMENSIONING AND TOLERANCING PER
  - MIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
     CONTROLLING DIMENSION: MILLIMETER.
     DIMENSION A DOES NOT INCLUDE MOLD FLASH, PROTRUSIONS OR GATE BURRS.
     MOLD FLASH OR GATE BURRS SHALL NOT
  - EXCEED 0.15 (0.006) PER SIDE.

    4. DIMENSION B DOES NOT INCLUDE INTERLEAD FLASH OR PROTRUSION.
    INTERLEAD FLASH OR PROTRUSION SHALL
  - NOT EXCEED 0.25 (0.010) PER SIDE.
    5. DIMENSION K DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.08 (0.003) TOTAL IN EXCESS OF THE K DIMENSION AT MAXIMUM MATERIAL CONDITION. 6. TERMINAL NUMBERS ARE SHOWN FOR

  - 7. DIMENSION A AND B ARE TO BE DETERMINED AT DATUM PLANE -W-.

	MILLIN	IETERS	INC	HES
DIM	MIN	MAX	MIN	MAX
Α	4.90	5.10	0.193	0.200
В	4.30	4.50	0.169	0.177
С		1.20		0.047
D	0.05	0.15	0.002	0.006
F	0.50	0.75	0.020	0.030
G	0.65	BSC	0.026 BSC	
Н	0.50	0.60	0.020	0.024
J	0.09	0.20	0.004	0.008
J1	0.09	0.16	0.004	0.006
Κ	0.19	0.30	0.007	0.012
K1	0.19	0.25	0.007	0.010
٦	6.40 BSC 0.252 BSC		BSC	
М	0 °	8 °	0 °	8 °

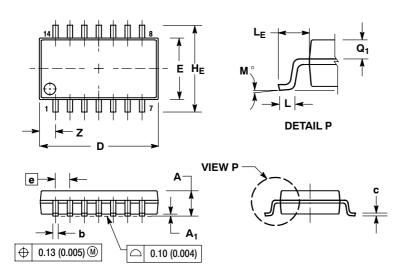
#### **SOLDERING FOOTPRINT\***



\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

#### PACKAGE DIMENSIONS

SOEIAJ-14 CASE 965-01 ISSUE A



#### NOTES:

- 1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
- CONTROLLING DIMENSION: MILLIMETER.
  DIMENSIONS D AND E DO NOT INCLUDE
- DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH OR PROTRUSIONS AND ARE MEASURED AT THE PARTING LINE. MOLD FLASH OR PROTRUSIONS SHALL NOT EXCEED 0.15 (0.006) PER SIDE.
- TERMINAL NUMBERS ARE SHOWN FOR REFERENCE ONLY.
- 5. THE LEAD WIDTH DIMENSION (b) DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.80 (0.003) TOTAL IN EXCESS OF THE LEAD WIDTH DIMENSION AT MAXIMUM MATERIAL CONDITION. DAMBAR CANNOT BE LOCATED ON THE LOWER RADIUS OR THE FOOT. MINIMUM SPACE BETWEEN PROTRUSIONS AND ADJACENT LEAD TO BE 0.46 (0.018).

	MILLIMETERS		INC	HES
DIM	MIN	MAX	MIN	MAX
Α		2.05		0.081
A <sub>1</sub>	0.05	0.20	0.002	0.008
b	0.35	0.50	0.014	0.020
C	0.10	0.20	0.004	0.008
D	9.90	10.50	0.390	0.413
Е	5.10	5.45	0.201	0.215
е	1.27	BSC	0.050	BSC
HE	7.40	8.20	0.291	0.323
0.50	0.50	0.85	0.020	0.033
LE	1.10	1.50	0.043	0.059
М	0 °	10°	0 °	10°
$Q_1$	0.70	0.90	0.028	0.035
Z		1.42		0.056

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